

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
		Examiner Ponder N. Thompson-Rummel	Art Unit 1753	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2004/0110085	06-2004	Iwai et al.	430/270.1
*	B US-2004/0029037	02-2004	Kamabuchi et al.	430/270.1
C	US-			
D	US-			
E	US-			
F	US-			
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I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 2003167347 A	06-2003	Japan	HANEDA et al.	
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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